

UNISONIC TECHNOLOGIES CO., LTD

2N55Q-TA **Preliminary Power MOSFET**

2A, 550V N-CHANNEL **POWER MOSFET**

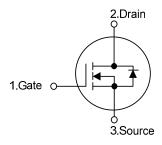
DESCRIPTION

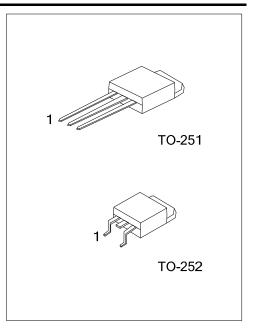
The UTC 2N55Q-TA is a high voltage power MOSFET designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and high rugged avalanche characteristics. This power MOSFET is usually used in high speed switching applications of switching power supplies and adaptors.

FEATURES

- * $R_{DS(ON)} \le 7.6 \Omega @ V_{GS} = 10V, I_D = 1.0A$
- * Fast switching capability
- * Avalanche energy tested
- * Improved dv/dt capability, high ruggedness



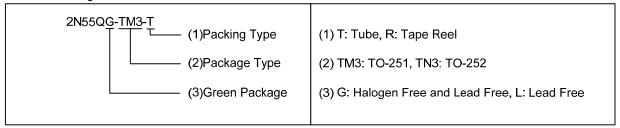




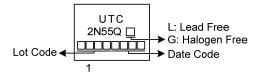
ORDERING INFORMATION

Ordering Number		Doolsons	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
2N55QL-TM3-T	2N55QG-TM3-T	TO-251	G	D	S	Tube	
2N55QL-TN3-R	2N55QG-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



MARKING



www.unisonic.com.tw 1 of 6

■ **ABSOLUTE MAXIMUM RATINGS** (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	550	V
Gate-Source Voltage		V_{GSS}	±30	V
Continuous Drain Current		I_D	2	Α
Pulsed Drain Current (Note 2)		I_{DM}	4	Α
Avalanche Energy Si	ingle Pulsed (Note 3)	E _{AS}	54	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	3	V/ns
Power Dissipation		P_D	30	W
Junction Temperature		TJ	+150	°C
Storage Temperature		T_{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 30mH, I_{AS} = 1.9A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25°C
- 4. $I_{SD} \le 3.0 A$, di/dt $\le 200 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25 ^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATING	UNIT	
Junction to Ambient	θ_{JA}	110	°C/W	
Junction to Case	θ_{JC}	4.16 (Note)	°C/W	

Note: Device mounted on FR-4 substrate Pc board, 2oz copper, with 1inch square copper plate.

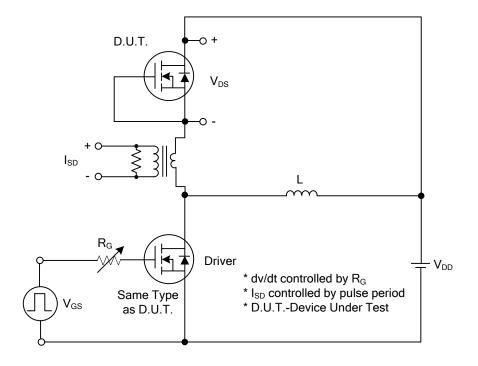
■ **ELECTRICAL CHARACTERISTICS** (T_J =25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	550			V
Drain-Source Leakage Current	I _{DSS}	$V_{DS} = 550V, V_{GS} = 0V$			10	μA
Forward	I _{GSS}	$V_{GS} = 30V, V_{DS} = 0V$			100	nA
Gate- Source Leakage Current Reverse		$V_{GS} = -30V, V_{DS} = 0V$			-100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_D = 250 \mu A$ 2.			4.0	V
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} = 10V, I _D = 1.0A			7.6	Ω
DYNAMIC CHARACTERISTICS				ā.		_
Input Capacitance	C _{ISS}			134		pF
Output Capacitance	Coss	V _{DS} =25V, V _{GS} =0V, f=1.0MHz		21		pF
Reverse Transfer Capacitance	C _{RSS}			3.5		pF
SWITCHING CHARACTERISTICS				ā.		_
Total Gate Charge (Note 1)	Q_G	\ -440\\ \ \ -10\\ -24		8.5		nC
Gate-Source Charge	Q_GS	V_{DS} =440V, V_{GS} =10V, I_{D} =2A		2.5		nC
Gate-Drain Charge	Q_GD	I _G =1mA (Note 1, 2)		1		nC
Turn-On Delay Time (Note 1)	t _{D(ON)}			4		ns
Turn-On Rise Time	t _R	V_{DS} =100V, V_{GS} =10V, I_{D} =2A,		16		ns
Turn-Off Delay Time	t _{D(OFF)}	R _G =25Ω (Note 1, 2)		15		ns
Turn-Off Fall Time	t _F			26		ns
DRAIN-SOURCE DIODE CHARACTERIST	ICS AND MA	XIMUM RATINGS				
Maximum Continuous Drain-Source Diode					2	Α
Forward Current	Is					^
Maximum Pulsed Drain-Source Diode	I _{SM}				4	Α
Forward Current	ISM				7	^
Drain-Source Diode Forward Voltage	V_{SD}	I _S =2.0A , V _{GS} =0V			1.4	V
(Note 1)	∨ SD	15-2.0/1, V GS-0 V			1.7	v
Reverse Recovery Time (Note 1)	t _{rr}	I _S =2.0A , V _{GS} =0V		180		ns
Reverse Recovery Charge	Q_{rr}	di/dt=100A/µs		1.5		μC

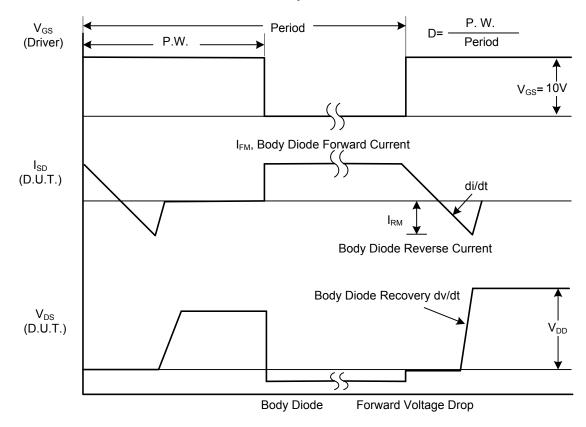
Notes: 1. Pulse Test: Pulse width \leq 300 μ s, Duty cycle \leq 2%.

^{2.} Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

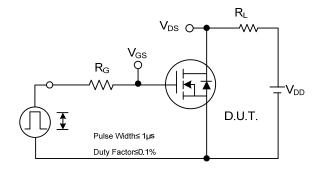


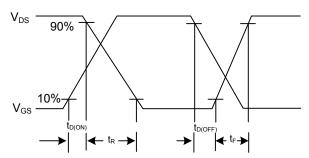
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

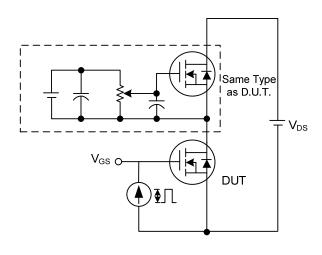
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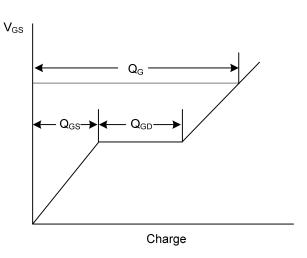




Switching Test Circuit

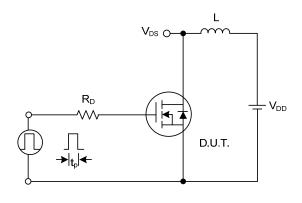
Switching Waveforms

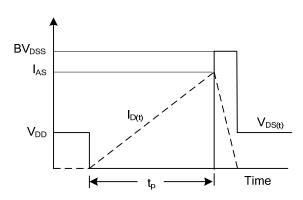




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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